

AMENDMENTS TO THE CLAIMS

1. (Original) A scanning electron microscope, comprising an electron source; a focusing lens which focuses a primary electron beam emitted from the electron source; a porous electrode, which forms an electric field to energy-filter electrons obtained as a result of irradiation of a sample by said primary electron beam, focused by the focusing lens; and a first electron detector which detects electrons which have passed through the porous electrode; characterized in further comprising:

a porous structure, positioned nearer to said sample than said porous electrode;

a deflector, positioned nearer to said sample than the porous structure, and which deflects electrons away from the axis of said primary electron beam; and,

a second electron detector, which detects electrons deflected by the deflector.

2 through 18 (cancelled).